PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Toshinori NAGAHASHI et al.

Application No.: New U.S. Patent Application

Filed: December 15, 2003 Docket No.: 118105

For: PICTURE LAYOUT PROCESSING APPARATUS, PICTURE LAYOUT PROCESSING METHOD, AND PROGRAM THEREFOR

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- 2. Relevance of the non-English language reference 1 is discussed in the present specification.
- 3. English-language Abstracts of the non-English language references 1 and 2 are attached hereto.

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4. A computer-generated English translation of the following Japanese Patent Publications have been obtained from the website of the Japanese Patent Office ([http://www.jpo.go.jp]), and are attached, but have not been reviewed for accuracy. See References 1 and 2.

Respectfully submitted,

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Date: December 15, 2003

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